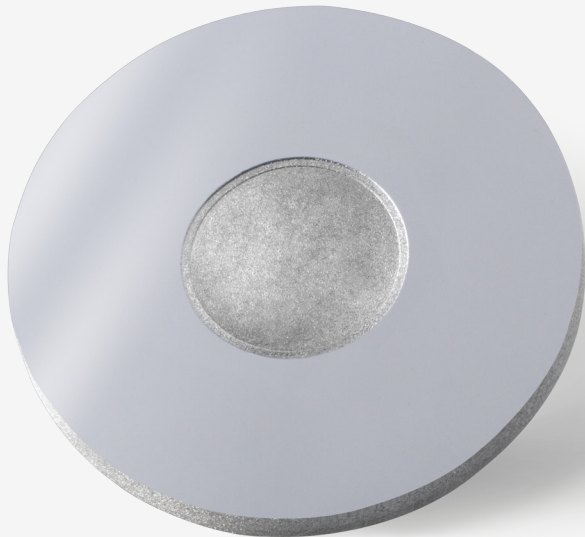
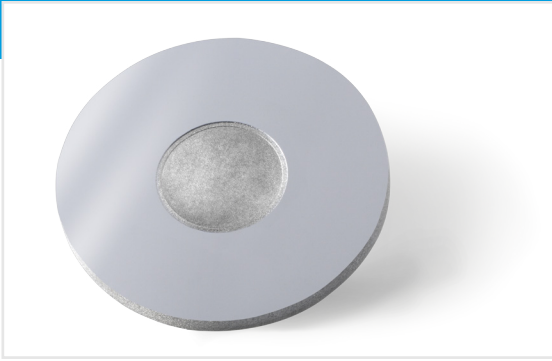


Zero Diffraction Plates



- Totally customized
- Low and medium volumes
- Any diameters from 10 mm to 100 mm
- Specific orientations for spectroscopy
- Any Thicknesses from 500 μm up to 5 mm
- Cavity on option

Zero Diffraction Plates

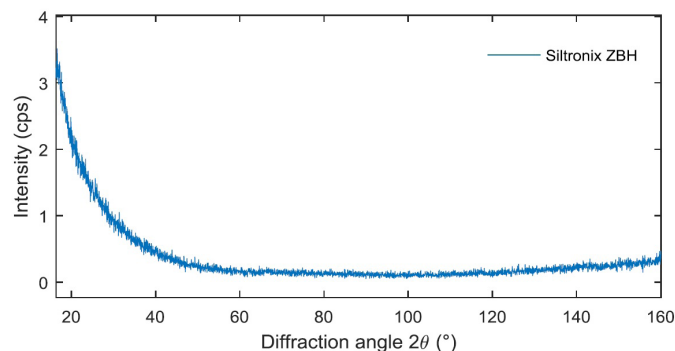


- Zero diffraction plates for X-Ray spectroscopy, also named Zero Background Holder are used for diffraction (XRD) analysis to insure a non-destructive analytical method.
- The Zero Background Holders are made of 9N semiconductor grade silicon. The single crystals are generally used for powder analysis more or less condensed.

Sil'tronix ST, expert in the manufacturing of customized silicon crystals, aims to provide qualitative solutions for the X-ray diffraction analysis

Crystal	Silicon, P-type B doped	
Orientation	On request, (510), (911), (100)9°(001), ...	
Orientation accuracy	0.2°	
Surface	Top side optical polished	
Cavity diameter	8 mm, depth 0,2 mm	
	Other dimensions on request	
	Min.	Max.
Thickness	500 µm	5000 µm
Resistivity (Ohms.cm)	10	50
Diameter (mm)	10	48

By using the crystal as background plate, the XRD pattern achieved is absolutely clean (No diffraction on X-rays). Even at very low-intensity, samples' Bragg reflections can be easily detected.



No diffraction on X-rays over the 20° to 160° range

Cavity zero diffraction plate is made of silicon cut with a special orientation in order to be invisible on x-rays:

- All those values and parameters can be adjusted on customer' request.
- Perfect for sample holder of powder XRD, which has no background noise from 10 to 120 degree (2θ angle Cu Ka X-Ray).
- Compatible with the majority of XRD equipments such as Siemens, Scinta, Bruker or Rigaku



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